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Confirmation Letter

To,

JETIR.

Dheeraj

Published in : Volume 5 | Issue 2 | 2018-02-28



Subject: Publication of paper at International Journal of Emerging Technologies and Innovative Research.

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: Dheeraj, Dr. Chhavi Rana Authors

Thank you very much for publishing your article in JETIR. We would appreciate if you continue your support and keep sharing your knowledge by writing for our journal JETIR.















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